

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 09/933,468 Applicant : Christopher S. MacLellan Filed : August 20, 2001 T.C./A.U. : 2138 Examiner : John J. Tabone, Jr. Docket No. : EMC-01-018 Customer No. : 24227	Confirmation No.: 5620
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Certificate of Mailing or Transmission 37 C.F.R. § 1.8

I hereby certify that this correspondence is being transmitted by facsimile on the date shown below to the Patent and Trademark Office at 571-273-8300.

Typed or printed name of person signing this Certificate:

Linda Valanzola

6/12/06

Date

Linda Valanzola

Signature

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

DECLARATION UNDER 37 C.F.R. §1.131

1. I, Christopher S. MacLellan, am the inventor of the above-referenced U.S. Patent Application No. 09/933,468 entitled "Testing System and Method of Using Same."
2. Prior to September 14, 2000, I conceived of, and reduced to practice, the invention described and claimed in U. S. Patent Application No. 09/933,468, as evidenced by source code, a portion of which being attached hereto as Exhibit A. The code was created on or before September 14, 2000 as is evidenced by the time stamp at the top of the file of the Exhibit indicating that the file A20SVC.v was last modified on September 14, 2000.

Application No. 09/933,468

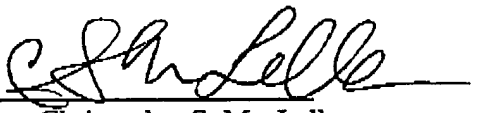
Docket No. EMC-01-018

Since this is the assignee's proprietary source code, only a portion of the code is included in the Exhibit. The code in its entirety comprises the third logic section recited in the claims.

Exhibit B is an email dated March 20, 2001 in which an invention disclosure conference is scheduled. One of the invention disclosures to be discussed at that conference is the invention described in this U. S. Patent Application No. 09/933,468, i.e., Docket No. EMC-01-018. This invention disclosure is attached as Exhibit C. I note that, although the "Date of Idea (or first disclosure either or written to others)" indicates a date of 11/15/01, this is a typographical error. The intended date was 11/15/2000, which was the date that I first disclosed the invention to others. The typographical error should be obvious, given that the invention disclosure conference was scheduled in March 2001 and the patent application was filed in August 2001.

3. All of the statements made herein of my own knowledge are true and all statements made on information and belief are believed to be true. These statements are made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment or both, under § 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application and any patent issuing thereon.

6-12-2006
Date of Signature

By: 
Christopher S. MacLellan

```
> ls -lat A20SVC.v
-rw-r--r--  1 chrismac symmem      101745 Sep 14  2000 A20SVC.v
> cat A20SVC.v
/* A20 Service Processor */
```

```

module A20SVC(CLOCK,
    RESET,
    SRESET,
    MID,

    // UI A Interface
    REQA,      // 0 = Request
    GNTA,      // 0 = Request grant
    TAGA,      // 18-bit TAG field from UI
    CMDA,      // 18-bit COMMAND field from UI
    AD2A,      // 18-bit ADDRESS 2 field from UI
    AD1A,      // 18-bit ADDRESS 1 field from UI
    AD0A,      // 18-bit ADDRESS 0 field from UI
    SDIA,      // 18-bit service data from UI
    SDOA,      // 18-bit service data to UI
    SDCRC1A,   // 18-bit Service data CRC high from UI
    SDCRC0A,   // 18-bit Service data CRC low from UI
    SDONEA,    // 1 = Service Done to UI
    SDRA,      // 1 = Service Data request to UI
    SDVA,      // 1 = Service Data valid to UI
    SERRA,     // 1 = Service Error to UI
    SCRCEA,    // 1 = Service Data CRC Error to UI
    INTERRA,   // 1 = Internal Error to UI
    NOCYCA,    // 1 = No Cycle Indication from UI
    CYCDONEA,  // 1 = Cycle Done Indication from UI
    AW,        // 1 = UI connected with W port
    AX,        // 1 = UI connected with X port
    AY,        // 1 = UI connected with Y port
    AZ,        // 1 = UI connected with Z port
    UTMOVALA,  // 14-bit Upper Timeout Value to UI
    DIAGA,     // 46-bit Diagnostic mode register to UI
    STATA,     // 64-bit Error/Event conduit from UI

    // UI B Interface
    REQB,      // 0 = Request
    GNTB,      // 0 = Request grant
    TAGB,      // 18-bit TAG field from UI
    CMDB,      // 18-bit COMMAND field from UI
    AD2B,      // 18-bit ADDRESS 2 field from UI
    AD1B,      // 18-bit ADDRESS 1 field from UI
    AD0B,      // 18-bit ADDRESS 0 field from UI
    SDIB,      // 18-bit service data from UI
    SDOB,      // 18-bit service data to UI
    SDCRC1B,   // 18-bit Service data CRC high from UI
    SDCRC0B,   // 18-bit Service data CRC low from UI
    SDONEB,    // 1 = Service Done to UI
    SDRB,      // 1 = Service Data request to UI
    SDVB,      // 1 = Service Data valid to UI
    SERRB,     // 1 = Service Error to UI
    SCRCEB,    // 1 = Service Data CRC Error to UI
    INTERRB,   // 1 = Internal Error to UI
    NOCYCB,    // 1 = No Cycle Indication from UI

```

hibit A
 C.F.R. §1.131 Declaration
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```

CYCDONEB, // 1 = Cycle Done Indication from UI
BW,       // 1 = UI connected with W port
BX,       // 1 = UI connected with X port
BY,       // 1 = UI connected with Y port
BZ,       // 1 = UI connected with Z port
UTMOVALB, // 14-bit Upper Timeout Value to UI
DIAGB,    // 46-bit Diagnostic mode register to UI
STATB,    // 64-bit Error/Event conduit from UI

// UI C Interface
REQC,     // 0 = Request
GNTC,     // 0 = Request grant
TAGC,     // 18-bit TAG field from UI
CMDC,     // 18-bit COMMAND field from UI
AD2C,     // 18-bit ADDRESS 2 field from UI
AD1C,     // 18-bit ADDRESS 1 field from UI
AD0C,     // 18-bit ADDRESS 0 field from UI
SDIC,     // 18-bit service data from UI
SDOC,     // 18-bit service data to UI
SDONEC,   // 1 = Service Done to UI
SDCRC1C,  // 18-bit Service data CRC high from UI
SDCRC0C,  // 18-bit Service data CRC low from UI
SDRC,     // 1 = Service Data request to UI
SDVC,     // 1 = Service Data valid to UI
SERRC,    // 1 = Service Error to UI
SCRCEC,   // 1 = Service Data CRC Error to UI
INTERRC,  // 1 = Internal Error to UI
NOCYCC,   // 1 = No Cycle Indication from UI
CYCDONEC, // 1 = Cycle Done Indication from UI
CW,       // 1 = UI connected with W port
CX,       // 1 = UI connected with X port
CY,       // 1 = UI connected with Y port
CZ,       // 1 = UI connected with Z port
UTMOVALC, // 14-bit Upper Timeout Value to UI
DIAGC,    // 46-bit Diagnostic mode register to UI
STATC,    // 64-bit Error/Event conduit from UI

// UI D Interface
REQD,     // 0 = Request
GNTD,     // 0 = Request grant
TAGD,     // 18-bit TAG field from UI
CMDD,     // 18-bit COMMAND field from UI
AD2D,     // 18-bit ADDRESS 2 field from UI
AD1D,     // 18-bit ADDRESS 1 field from UI
AD0D,     // 18-bit ADDRESS 0 field from UI
SDID,     // 18-bit service data from UI
SDOD,     // 18-bit service data to UI
SDCRC1D,  // 18-bit Service data CRC high from UI
SDCRC0D,  // 18-bit Service data CRC low from UI
SDONED,   // 1 = Service Done to UI
SDRD,     // 1 = Service Data request to UI
SDVD,     // 1 = Service Data valid to UI
SERRD,    // 1 = Service Error to UI
SCRCED,   // 1 = Service Data CRC Error to UI
INTERRD,  // 1 = Internal Error to UI
NOCYCD,   // 1 = No Cycle Indication from UI
CYCDONED, // 1 = Cycle Done Indication from UI

```

Exhibit B
C.F.R. §1.131 Declaration
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Mazzarella, Julie
From: Mazzarella, Julie
Sent: Tuesday, March 20, 2001 11:27 AM
To: walton, john (BMC Eng); maclellan, chris; bermingham, mike; Gupta, Krish; Gagne, Christopher
Subject: Disclosure Conference April 9, 10a.m.-12p.m., Conf. Rm. 21-28 (171 South St.)

Gentlemen,

You will be meeting on Monday, April 9, from 10 a.m. to 12 p.m. in Conference Room 21-28 at 171 South Street to discuss the following new invention disclosures:

1. [REDACTED]
2. [REDACTED]
3. *System and Method for Reliably Testing Embedded Memory* by Chris MacLellan (EMC-01-018).

Thanks,

Julia Mazzarella
Patent Administrator
Office of the General Counsel
EMC Corporation
35 Parkwood Drive
Hopkinton, MA 01748

Exhibit C
' C.F.R. §1.131 Declaration
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EMC-01-018

INVENTION RECORD/DISCLOSURE

1. **Title:** System and Method for Reliably Testing Embedded Memory
2. **Description and purpose of the Invention (include drawings, memos, or other explanatory material:** When embedding memory structures (such as SRAM) into a custom design (such as an ASIC), testing the memory during manufacture of the chip is important. This system provides a way to test the memory, not only during chip manufacture, but also at any time during board test and system test. This system also provides a way to inject a fault into the memory to test the test circuit itself. There is protection built into the system which add to the reliability of the design.
3. **Former approaches and disadvantages:** Prior approaches either required a lot of manual test vector generation, additional chip pins dedicated to the memory test circuit, or both. They also took away from the reliability of the design.
4. **Advantages of Invention over former approaches:** This system does not require additional pins or manual test vectors. It also has built-in protection against inadvertent test circuit interference with system operation.
5. **Inventors:** Christopher S. MacLellan
6. **Date of Idea (or first disclosure either oral or written to others):** 11/15/01